

<b>Notice of References Cited</b>		Application/Control No.	Applicant(s)/Patent Under Reexamination WEI ET AL.	
		Examiner RICHARD BOWEN	Art Unit 2156	Page 1 of 1

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*	B	US-7,174,343 B2	02-2007	Campos et al.	707/737
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*	F	US-6,138,117	10-2000	Bayardo, Roberto Javier	1/1
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	V	Wang et al., "CLOSET+: Searching for the Best Strategies for Mining Frequent Closed Itemsets," 2003, ACM, SESSION: Research track, Pages 236-45
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\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)  
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.